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TriQuint Semiconductor, Inc., Beaverton, OR, USA

\*EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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PTO/SB/08 (11-90) Patent and Trademark Office: U.S.DEPARTMENT OF COMMERC'E citation if not in conformance and not considered. Include copy of this form with next communication to the applicant. EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP \$ 609; Draw line through EC/88/C **EXYMINES** OTHER DOCUMENTS (Including Author, Tide, Dain, Perdinent Pages, Ett.) AES WO REBINUM TNEMUCCOD MINUOD \$28CLASS crrs2 FOREIGN PATENT DOCUMENTS 600% H800265 .13 , u à . 10 REXEMBLE STATEMENT STAIRSORGE TE DOCUMENT NUMBER BTAG SUBCLASS U. S. PATENT DOCUMENTS 24 / T</ 3 HOU BOILT (Use several sheets if necessary) CINC ASSE MUNI ASSES 2813 IN AN APPLICATION toptomi den Bose, er, nr. 19255/01 INFORMATION DISCLOSURE CITATION Ebe '05161 **6441-0T9 m10-1** 1 to -1 ment?